

General Description

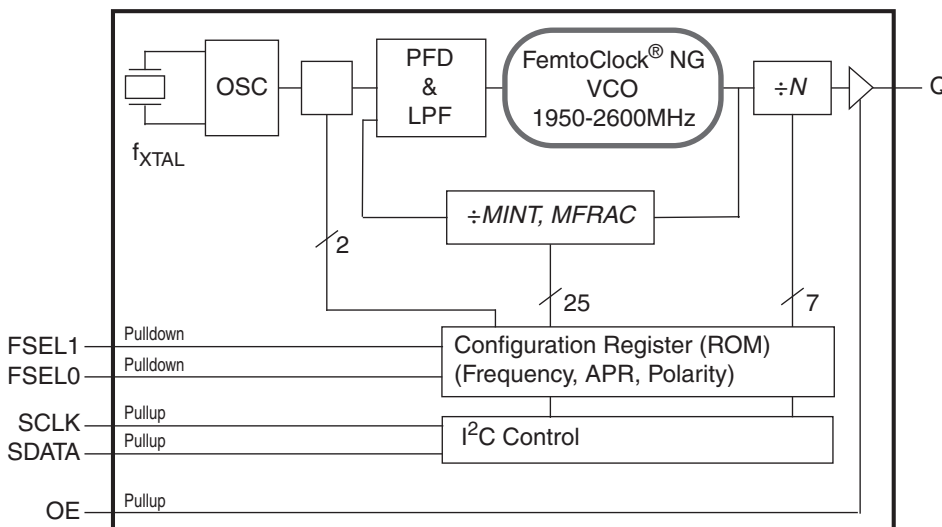
The IDT8N0Q001 is a Quad-Frequency Programmable Clock Oscillator with very flexible frequency programming capabilities. The device uses IDT's fourth generation FemtoClock® NG technology for an optimum of high clock frequency and low phase noise performance. The device accepts 2.5V or 3.3V supply and is packaged in a small, lead-free (RoHS 6) 10-lead ceramic 5mm x 7mm x 1.55mm package.

Besides the 4 default power-up frequencies set by the FSEL0 and FSEL1 pins, the IDT8N0Q001 can be programmed via the I²C interface to output clock frequencies between 15.476 to 260MHz to a very high degree of precision with a frequency step size of $435.9\text{Hz} \div N$ (N : PLL post divider). Since the FSEL0 and FSEL1 pins are mapped to 4 independent PLL M and N divider registers (P, MINT, MFRAC and N), reprogramming those registers to other frequencies under control of FSEL0 and FSEL1 is supported. The extended temperature range supports wireless infrastructure, telecommunication and networking end equipment requirements.

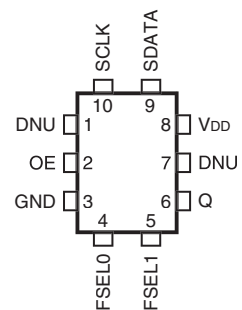
Features

- Fourth generation FemtoClock® NG technology
- Programmable clock output frequency from 15.476MHz to 260MHz
- Four power-up default frequencies (see part number order codes), re-programmable by I²C
- I²C programming interface for the output clock frequency and internal PLL control registers
- Frequency programming resolution is $435.9\text{Hz} \div N$
- One 2.5V, 3.3V LVC MOS clock output
- Two control inputs for the power-up default frequency
- LVC MOS/LVTTL compatible control inputs
- RMS phase jitter @ 156.25MHz (12kHz - 20MHz): 0.250ps (typical)
- RMS phase jitter @ 156.25MHz (1kHz - 40MHz): 0.290ps (typical)
- 2.5V or 3.3V supply
- -40°C to 85°C ambient operating temperature
- Available in Lead-free (RoHS 6) package

Block Diagram



Pin Assignment



IDT8N0Q001 Rev H
10-lead ceramic 5mm x 7mm x 1.55mm
package body
CD Package
Top View

Pin Descriptions and Characteristics

Table 1. Pin Descriptions

Number	Name	Type		Description
1, 7	DNU			Do not use. Do not connect
2	OE	Input	Pullup	Output enable pin. See Table 3B for function. LVCMOS/LVTTL interface levels.
3	GND	Power		Power supply ground
4, 5	FSEL0, FSEL1	Input	Pulldown	Default frequency select pins. LVCMOS/LVTTL interface levels. Refer to the <i>FemtoClock NG Ceramic-Package XO and VCXO Ordering Product Information</i> document for default frequency order codes.
6	Q	Output		Clock output. LVCMOS interface levels.
8	V _{DD}	Power		Positive supply pin.
9	SDATA	Input	Pullup	I ² C Data Input. LVCMOS/LVTTL interface levels.
10	SCLK	Input	Pullup	I ² C Clock Input. LVCMOS/LVTTL interface levels.

NOTE: *Pullup* and *Pulldown* refer to internal input resistors. See Table 2, *Pin Characteristics*, for typical values.

Table 2. Pin Characteristics

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance	OE, SDATA, SCLK, FSEL[0:1]		4		pF
C _{PD}	Power Dissipation Capacitance	V _{DD} = 3.465V or 2.625V		8		pF
R _{PULLUP}	Input Pullup Resistor			50		kΩ
R _{PULLDOWN}	Input Pulldown Resistor			50		kΩ
R _{OUT}	Output Impedance	Q	V _{DD} = 3.3V		15	Ω
			V _{DD} = 2.5V		19	Ω

Function Tables

Table 3A. Default Frequency Selection

Input		Operation
FSEL1	FSEL0	
0 (default)	0 (default)	Default frequency 0
0	1	Default frequency 1
1	0	Default frequency 2
1	1	Default frequency 3

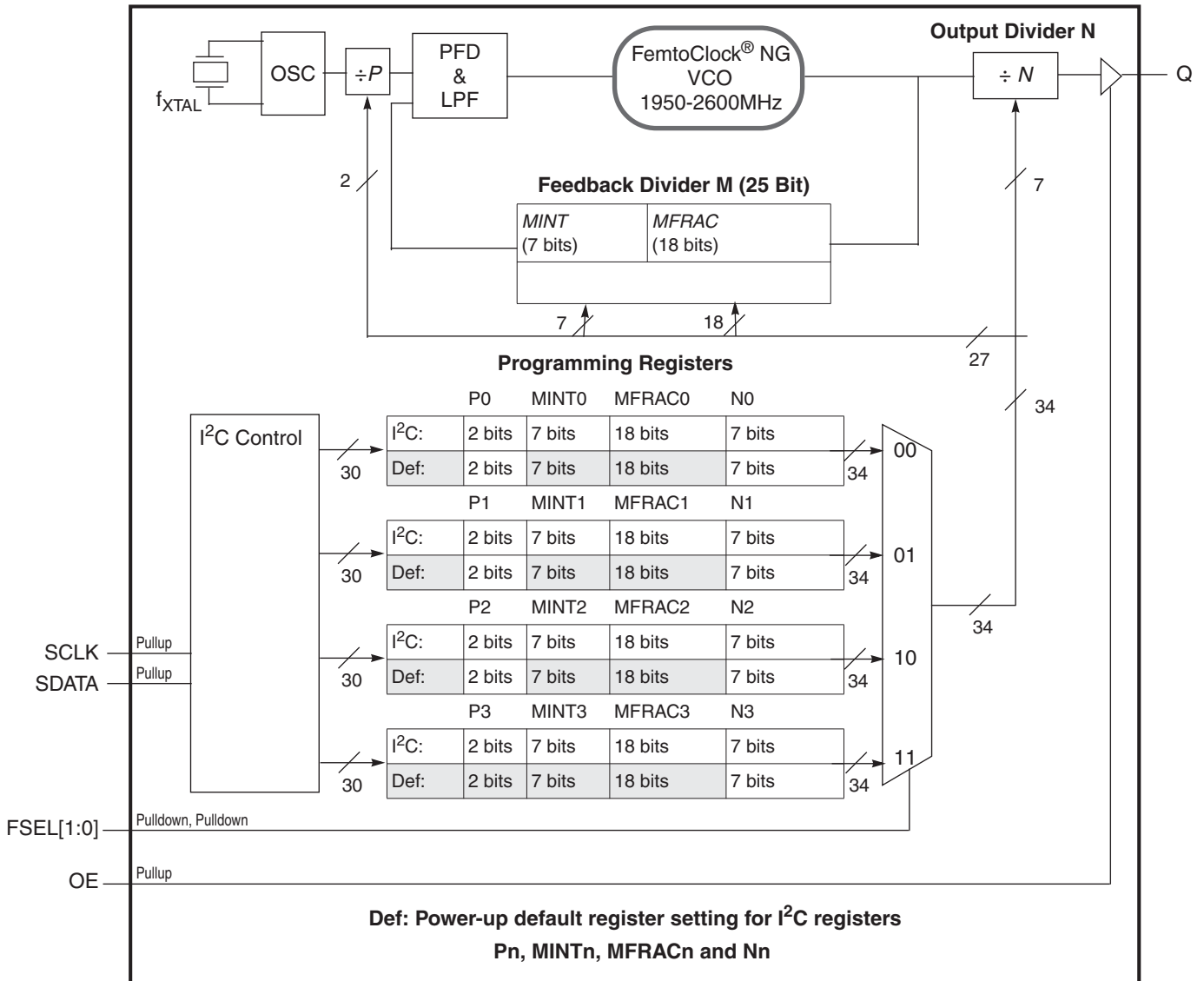
NOTE: The default frequency is the output frequency after power-up. One of four default frequencies is selected by FSEL[1:0]. See programming section for details.

Table 3B. OE Configuration

Input	Output Enable
OE	
0	Output Q are in high-impedance state.
1 (default)	Output is enabled.

NOTE: OE is an asynchronous control.

Block Diagram with Programming Registers



Principles of Operation

The block diagram consists of the internal 3rd overtone crystal and oscillator which provide the reference clock f_{XTAL} of either 114.285 MHz or 100 MHz. The PLL includes the FemtoClock NG VCO along with the Pre-divider (P), the feedback divider (M) and the post divider (N). The P , M , and N dividers determine the output frequency based on the f_{XTAL} reference and must be configured correctly for proper operation. The feedback divider is fractional supporting a huge number of output frequencies. The configuration of the feedback divider to integer-only values results in an improved output phase noise characteristics at the expense of the range of output frequencies. In addition, internal registers are used to hold up to four different factory pre-set P , M , and N configuration settings. These default pre-sets are stored in the I²C registers at power-up. Each configuration is selected via the FSEL[1:0] pins and can be read back using the SCLK and SDATA pins.

The user may choose to operate the device at an output frequency different than that set by the factory. After power-up, the user may write new P , N and M settings into one or more of the four configuration registers and then use the FSEL[1:0] pins to select the newly programmed configuration. Note that the I²C registers are volatile and a power supply cycle will reload the pre-set factory default conditions.

If the user does choose to write a different P , M , and N configuration, it is recommended to write to a configuration which is not currently selected by FSEL[1:0] and then change to that configuration after the I²C transaction has completed. Changing the FSEL[1:0] controls results in an immediate change of the output frequency to the selected register values. The P , M , and N frequency configurations support an output frequency range 15.476MHz to 260MHz.

The devices use the fractional feedback divider with a delta-sigma modulator for noise shaping and robust frequency synthesis capability. The relatively high reference frequency minimizes phase noise generated by frequency multiplication and allows more efficient shaping of noise by the delta-sigma modulator.

The output frequency is determined by the 2-bit pre-divider (P), the feedback divider (M) and the 7-bit post divider (N). The feedback divider (M) consists of both a 7-bit integer portion ($MINT$) and an 18-bit fractional portion ($MFRAC$) and provides the means for high-resolution frequency generation. The output frequency f_{OUT} is calculated by:

$$f_{OUT} = f_{XTAL} \cdot \frac{1}{P \cdot N} \cdot \left[MINT + \frac{MFRAC + 0.5}{2^{18}} \right]$$

The four configuration registers for the P , M ($MINT$ & $MFRAC$) and N dividers which are named P_n , $MINT_n$, $MFRAC_n$ and N_n with $n = 0$ to 3. “n” denominates one of the four possible configurations.

As identified previously, the configurations of P , M ($MINT$ & $MFRAC$) and N divider settings are stored in the I²C register, and the configuration loaded at power-up is determined by the FSEL[1:0] pins.

Table 4. Frequency Selection

Input		Selects	Register
FSEL1	FSEL0		
0 (def.)	0 (def.)	Frequency 0	P0, MINT0, MFRAC0, N0
0	1	Frequency 1	P1, MINT1, MFRAC1, N1
1	0	Frequency 2	P2, MINT2, MFRAC2, N2
1	1	Frequency 3	P3, MINT3, MFRAC3, N3

Frequency Configuration

An order code is assigned to each frequency configuration programmed by the factory (default frequencies). For available order codes, see the *FemtoClock NG Ceramic-Package XO and VCXO Ordering Product Information* document.

For more information and guidelines on programming of the device for custom frequency configurations, the register description, the selection of fractional and integer-feedback configurations and the serial interface description, see the *FemtoClock NG Ceramic 5x7 Module Programming Guide*.

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of the product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V_{DD}	3.6V
Inputs, V_I	-0.5V to $V_{DD} + 0.5V$
Outputs, V_O (LVCMOS)	-0.5V to $V_{DD} + 0.5V$
Outputs, I_O (SDATA)	10mA
Package Thermal Impedance, θ_{JA}	49.4°C/W (mps)
Storage Temperature, T_{STG}	-65°C to 150°C

DC Electrical Characteristics

Table 5A. Power Supply DC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Positive Supply Voltage		3.135	3.3	3.465	V
I_{DD}	Power Supply Current	No Load, OE = Low		127	145	mA

Table 5B. Power Supply DC Characteristics, $V_{DD} = 2.5V \pm 5\%$, $T_A = -40^\circ\text{C}$ to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Positive Supply Voltage		2.375	2.5	2.625	V
I_{DD}	Power Supply Current	No Load, OE = Low		123	140	mA

Table 5C. LVCMOS/LVTTL DC Characteristic, $V_{DD} = 3.3V \pm 5\%$ or $2.5V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V_{IH}	Input High Voltage	OE, SCLK, SDATA, FSEL [1:0]	$V_{DD} = 3.3V$	2		$V_{DD} + 0.3$	V
			$V_{DD} = 2.5V$	1.7		$V_{DD} + 0.3$	V
V_{IL}	Input Low Voltage	OE, SCLK, SDATA, FSEL [1:0]	$V_{DD} = 3.465V$	-0.3		0.8	V
			$V_{DD} = 2.5V$	-0.3		0.7	V
I_{IH}	Input High Current	OE	$V_{DD} = V_{IN} = 3.465V$ or $2.625V$			10	μA
		SDATA, SCLK	$V_{DD} = V_{IN} = 3.465V$ or $2.625V$			5	μA
		FSEL0, FSEL1	$V_{DD} = V_{IN} = 3.465V$ or $2.625V$			150	μA
I_{IL}	Input Low Current	OE	$V_{DD} = 3.465V$ or $2.625V$, $V_{IN} = 0V$	-500			μA
		SDATA, SCLK	$V_{DD} = 3.465V$ or $2.625V$, $V_{IN} = 0V$	-150			μA
		FSEL0, FSEL1	$V_{DD} = 3.465V$ or $2.625V$, $V_{IN} = 0V$	-5			μA
V_{OH}	Output High Voltage	Q	$V_{DD} = 3.465V$	2.4			V
			$V_{DD} = 2.625$	1.7			V
V_{OL}	Output Low Voltage	Q	$V_{DD} = 3.6V$ or 2.625			0.4	V

AC Electrical Characteristics

Table 6. AC Characteristics, $V_{DD} = 3.3V \pm 5\%$ or $2.5V \pm 5\%$, $T_A = -40^\circ C$ to $85^\circ C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f_{OUT}	Output Frequency Q, nQ	$P=1, N = 10...126$	15.476		260	MHz
f_I	Initial Accuracy	Measured at $25^\circ C$ at final test			± 10	ppm
f_S	Temperature Stability	Option code = A or B			± 100	ppm
		Option code = E or F			± 50	ppm
		Option code = K or L			± 20	ppm
f_A	Aging	Frequency drift over 10 year life			± 3	ppm
		Frequency drift over 15 year life			± 5	ppm
f_T	Total Stability	Option code A or B (10 year life)			± 113	ppm
		Option code E or F (10 year life)			± 63	ppm
		Option code K or L (10 year life)			± 33	ppm
$f_{jit(cc)}$	Cycle-to-Cycle Jitter; NOTE 1	$V_{DD} = 3.3V$		7	20	ps
		$V_{DD} = 2.5V$		9	24	ps
$f_{jit(per)}$	Period Jitter; NOTE 1	$V_{DD} = 3.3V$		2	4	ps
		$V_{DD} = 2.5V$		3	5	ps
$f_{jit}(\emptyset)$	RMS Phase Jitter (Random); $f_{XTAL} = 114.285MHz$ (0xxx order codes)	$17MHz \leq f_{out} \leq 260MHz$, Integration Range: 12kHz - 20MHz; NOTE 3, 4			1.360	ps
	RMS Phase Jitter (Random); $f_{XTAL} = 100MHz$ (1xxx order codes)	156.25MHz, Integration Range: 12kHz - 20MHz; NOTE 2		0.250	0.285	ps
	RMS Phase Jitter (Random); $f_{XTAL} = 100MHz$ (1xxx order codes)	156.25MHz, Integration Range: 1kHz - 40MHz		0.290	0.400	ps
	RMS Phase Jitter (Random); Fractional PLL feedback and $f_{XTAL} = 100.000MHz$ (2xxx order codes)	$17MHz \leq f_{out} \leq 260MHz$, Integration Range: 12kHz - 20MHz; NOTE 3, 4			1.000	ps
$\Phi_N(100)$	Single-side band phase noise, 100Hz from Carrier	156.25MHz		-94		dBc/Hz
$\Phi_N(1k)$	Single-side band phase noise, 1kHz from Carrier	156.25MHz		-119.7		dBc/Hz
$\Phi_N(10k)$	Single-side band phase noise, 10kHz from Carrier	156.25MHz		-129.6		dBc/Hz
$\Phi_N(100k)$	Single-side band phase noise, 100kHz from Carrier	156.25MHz		-137.8		dBc/Hz
$\Phi_N(1M)$	Single-side band phase noise, 1MHz from Carrier	156.25MHz		-139		dBc/Hz
$\Phi_N(10M)$	Single-side band phase noise, 10MHz from Carrier	156.25MHz		-154.16		dBc/Hz
t_R / t_F	Output Rise/Fall Time	$V_{DD} = 3.3V, 20\%$ to 80%	150	330	700	ps
		$V_{DD} = 2.5V, 20\%$ to 80%	150	410	800	ps
odc	Output Duty Cycle		45	50	55	%
t_{OSC}	Oscillator Start-Up Time				20	ms
t_{SET}	Output Frequency Settling Time after FSEL0 and FSEL1 Values are Changed				1	ms

Notes continued on next page.

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE: XTAL parameters (Initial Accuracy, temperature Stability, Aging and Total Stability) are guaranteed by manufacturing.

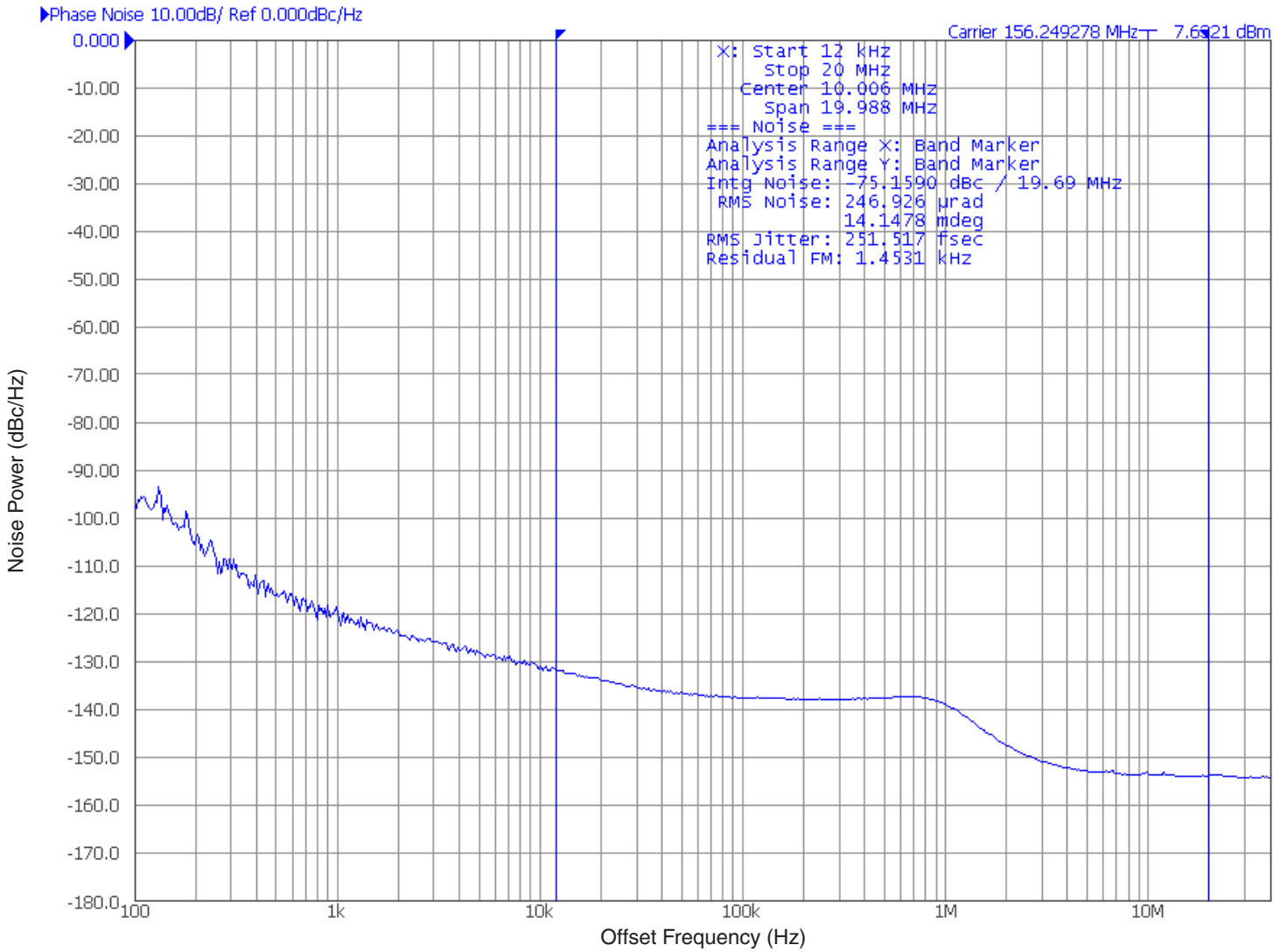
NOTE 1: This parameter is defined in accordance with JEDEC standard 65.

NOTE 2: Please refer to the phase noise plots.

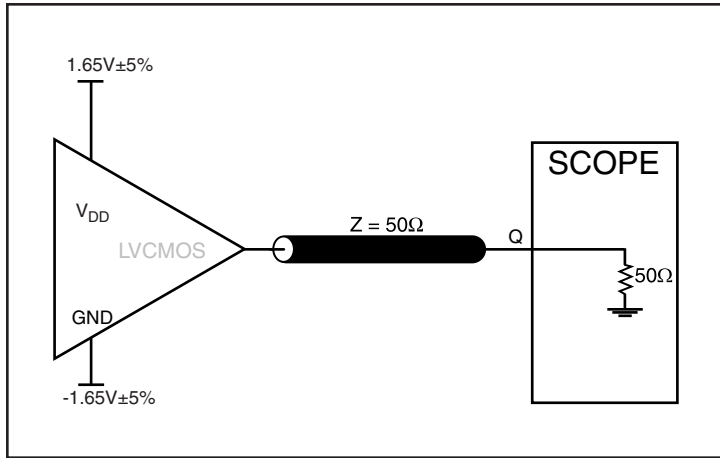
NOTE 3: Please see the FemtoClock NG Ceramic 5x7 Modules Programming guide for more information on PLL feedback modes and the optimum configuration for phase noise. Phase noise specification is applicable at MFRAC = 0.080 to 0.496 and MFRAC = 0.560 to 0.880.

NOTE 4: Integer PLL feedback is the default operation for the dddd = 1xxx order codes and configures DSM_ENA = 0 and ADC_EN = 0.

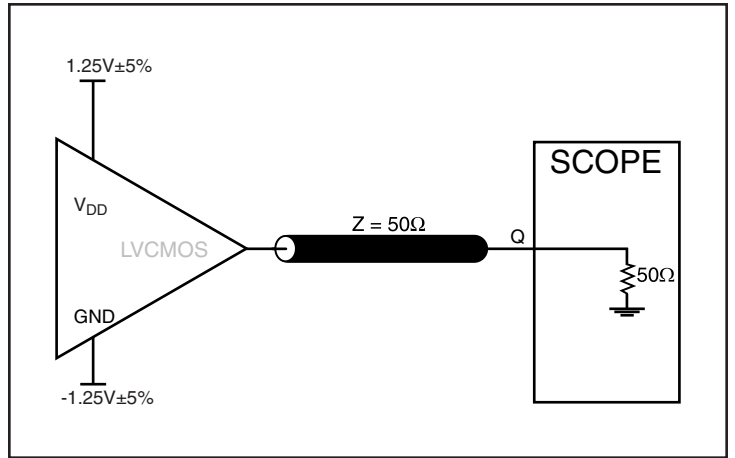
Typical Phase Noise at 156.25MHz (12kHz - 20MHz)



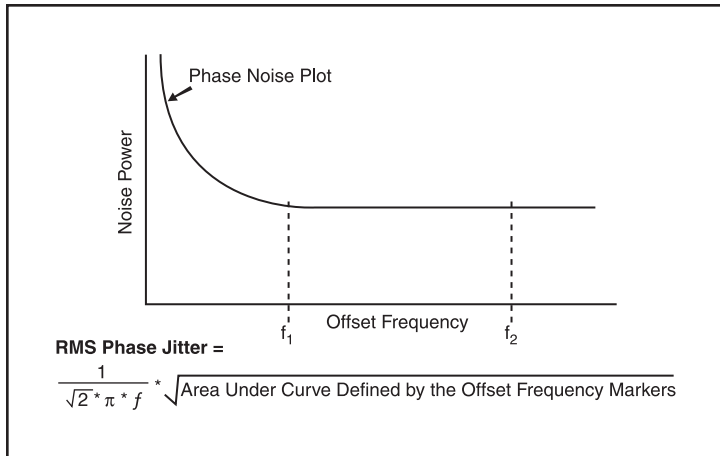
Parameter Measurement Information



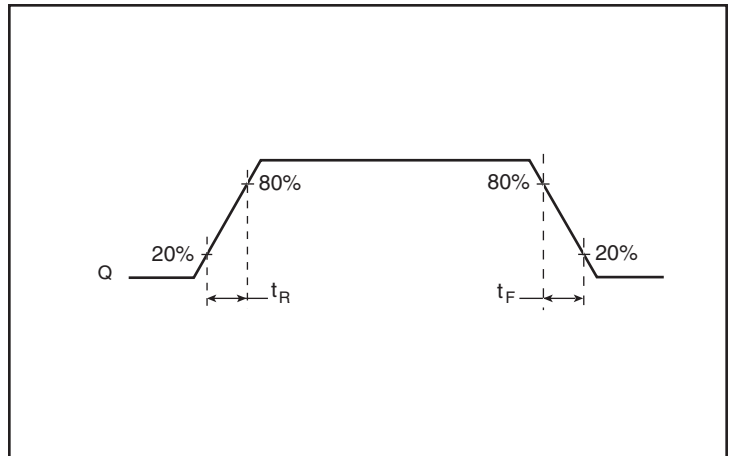
3.3V LVCMOS Output Load Test Circuit



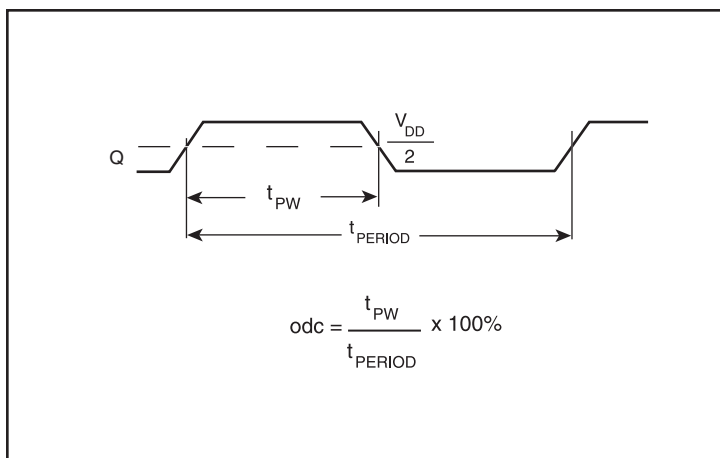
2.5V LVCMOS Output Load Test Circuit



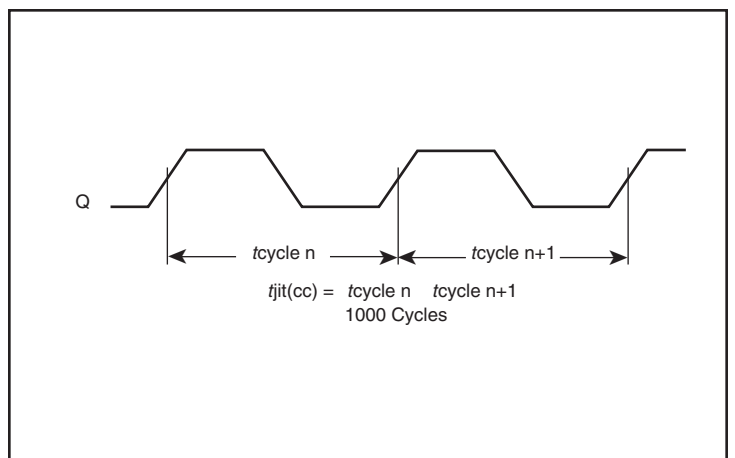
RMS Phase Jitter



Output Rise/Fall Time

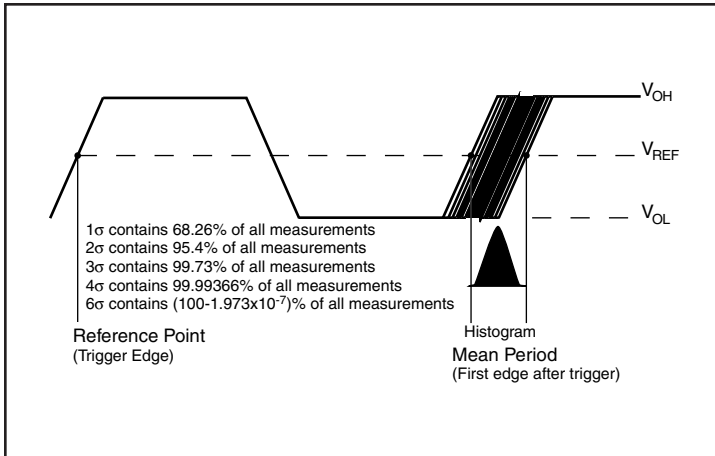


Output Duty Cycle/Pulse Width/Period



Cycle-to-Cycle Jitter

Parameter Measurement Information, continued



Period Jitter

Applications Information

Recommendations for Unused Input Pins

Inputs:

LVC MOS Select Pins

All control pins have internal pulldowns and pullups; additional resistance is not required but can be added for additional protection. A $1\text{k}\Omega$ resistor can be used.

Schematic Example

Figure 1 shows an example 8N0Q001 application schematic in which the device is operated at $V_{DD} = +3.3V$. The schematic example focuses on functional connections and is intended as an example only and may not represent the exact user configuration. Refer to the pin description and functional tables in the datasheet to ensure the logic control inputs are properly set. For example OE and FSEL[1:0] can be configured from an FPGA instead of set with pull up and pull down resistors as shown.

As with any high speed analog circuitry, the power supply pins are vulnerable to random noise, so to achieve optimum jitter performance isolation of the V_{DD} pin from power supply is required. In order to achieve the best possible filtering, it is recommended that the placement of the filter components be on the device side of the PCB as close to the power pins as possible. If space is limited, the $0.1\mu F$

capacitor on the V_{DD} pin must be placed on the device side with direct return to the ground plane though vias. The remaining filter components can be on the opposite side of the PCB.

Power supply filter component recommendations are a general guideline to be used for reducing external noise from coupling into the devices. The filter performance is designed for a wide range of noise frequencies. This low-pass filter starts to attenuate noise at approximately 10kHz. If a specific frequency noise component is known, such as switching power supplies frequencies, it is recommended that component values be adjusted and if required, additional filtering be added. Additionally, good general design practices for power plane voltage stability suggests adding bulk capacitance in the local area of all devices.

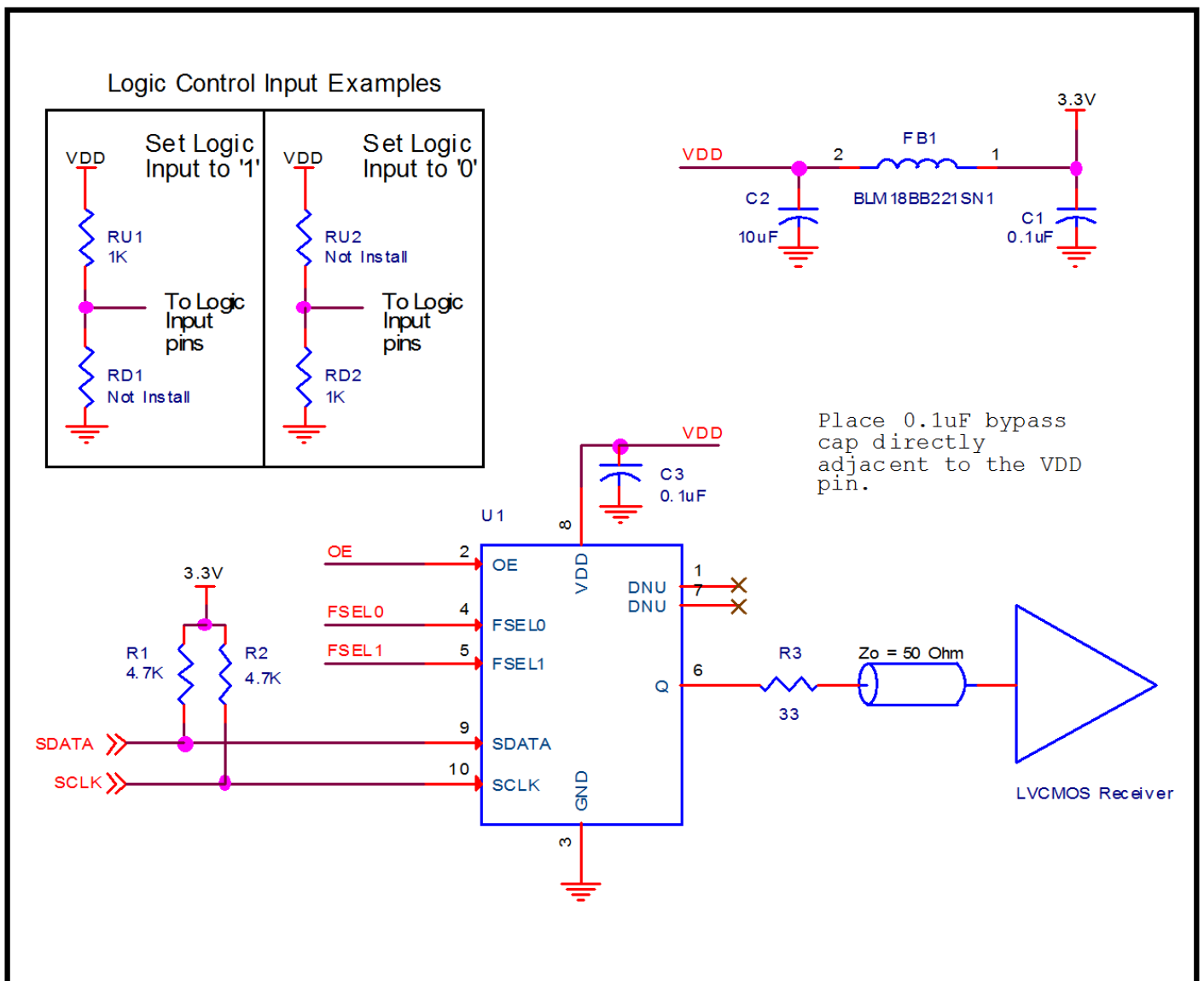


Figure 1. IDT8N0Q001 Schematic Example

Power Considerations

This section provides information on power dissipation and junction temperature for the IDT8N0Q001. Equations and example calculations are also provided.

1. Power Dissipation.

The total power dissipation for the IDT8N0Q001 is the sum of the core power plus the power dissipation in the load(s). The following is the power dissipation for $V_{DD} = 3.3V + 5\% = 3.465V$, which gives worst case results.

- Power (core)_{MAX} = $V_{DD_MAX} * I_{DD} = 3.465V * 145mA = 502.43mW$

Total Static Power:

$$= \text{Power (core)}_{MAX} = 502.43mW$$

Dynamic Power Dissipation at F_{OUT} (max)

$$\text{Total Power (F}_{OUT_MAX}) = [(C_{PD} * N) * \text{Frequency} * (V_{DD})^2] = [(8pF * 1) * 260MHz * (3.465V)^2] = 24.97mW$$

Total Power

$$\begin{aligned} &= \text{Static Power} + \text{Dynamic Power Dissipation} \\ &= 502.43mW + 24.97mW \\ &= 529.903mW \end{aligned}$$

2. Junction Temperature.

Junction temperature, T_j , is the temperature at the junction of the bond wire and bond pad, and directly affects the reliability of the device. The maximum recommended junction temperature is 125°C. Limiting the internal transistor junction temperature, T_j , to 125°C ensures that the bond wire and bond pad temperature remains below 125°C.

The equation for T_j is as follows: $T_j = \theta_{JA} * Pd_{total} + T_A$

T_j = Junction Temperature

θ_{JA} = Junction-to-Ambient Thermal Resistance

Pd_{total} = Total Device Power Dissipation (example calculation is in section 1 above)

T_A = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance θ_{JA} must be used. Assuming no air flow and a multi-layer board, the appropriate value is 49.4°C/W per Table 7 below.

Therefore, T_j for an ambient temperature of 85°C with all outputs switching is:

$$85^\circ C + 0.530W * 49.4^\circ C/W = 111^\circ C. \text{ This is below the limit of } 125^\circ C.$$

This calculation is only an example. T_j will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

Table 7. Thermal Resistance θ_{JA} for a 10-lead Ceramic 5mm x 7mm Package, Forced Convection

Meters per Second	θ_{JA} by Velocity		
	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	49.4°C/W	44.2°C/W	41.0°C/W

Reliability Information

Table 8. θ_{JA} vs. Air Flow Table for a 10-lead Ceramic 5mm x 7mm Package

θ_{JA} vs. Air Flow			
Meters per Second	0	1	2.5
Multi-Layer PCB, JEDEC Standard Test Boards	49.4°C/W	44.2°C/W	41.0°C/W

Transistor Count

The transistor count for IDT8N0Q001 is: 47,302

Package Outline and Package Dimensions

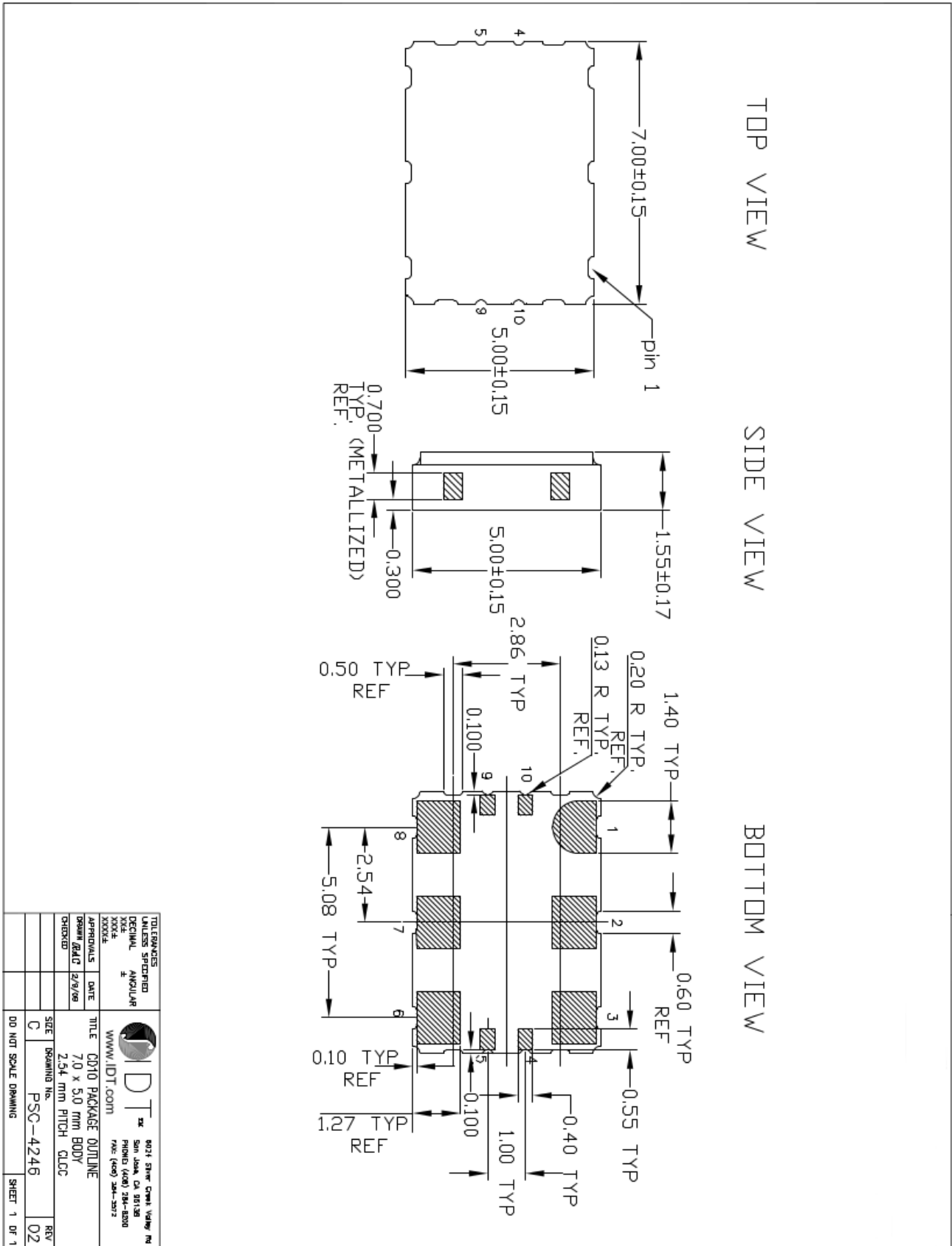


Table 9. Device Marking

Marking	Industrial Temperature Range ($T_A = -40^{\circ}\text{C}$ to 85°C)	Commercial Temperature Range ($T_A = 0^{\circ}\text{C}$ to 70°C)
		IDT8N0Q001yH- ddddCDI
y = Option Code, dddd =Default-Frequency and VCXO Pull Range		

NOTE: For available order codes, see the FemtoClock NG Ceramic-Package XO and VCXO Ordering Product Information document. For more information and guidelines on programming of the device for custom frequency configurations, programming for a specific VCXO pull range, the available APR (absolute pull range), the register description and the serial interface description, see the FemtoClock NG Ceramic 5x7 Module Programming Guide.

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